

“Internal calibration technique for HREM studies of nanoscale particles”. Schryvers D, Goessens C, Safran G, Toth L, Microscopy research and technique
T2 - JOINT MEETING OF DUTCH SOC FOR ELECTRON MICROSCOPY / BELGIAN
SOC FOR, ELECTRON MICROSCOPY / BELGIAN SOC FOR CELL BIOLOGY, DEC 10
11, 1992, ANTWERP, BELGIUM 25, 185 (1993). <http://doi.org/10.1002/jemt.1070250216>